

## N-channel MOSFET

### Features and Benefits

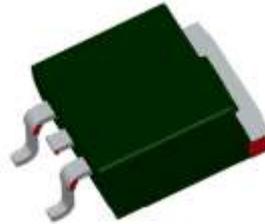
- R<sub>DS(on)</sub>: 6mΩ (max.)@25°C
- V<sub>DSS</sub>: 40V
- Built-in Protection zener Di between G-S.
- Avalanche energy capability guaranteed
- Trench MOSFET structure.
- High Reliability

### Applications

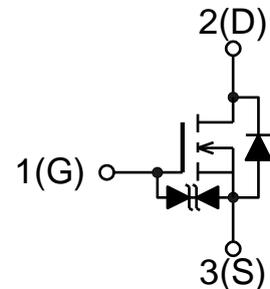
Various motor driving applications, such as power steering motors.  
 Replacement of mechanical relays.  
 High current switching.  
 For automotive

### Package

#### D2PAK



### Equivalent Circuit



### Absolute maximum ratings

(Ta=25°C)

Characteristic	Symbol	Rating	Unit
Drain to Source Voltage	V <sub>DSS</sub>	40	V
Gate to Source Voltage	V <sub>GSS</sub>	±20	V
Continuous Drain Current	I <sub>D</sub>	±70	A
Pulsed Drain Current	I <sub>D(pulse)</sub> <sup>*1</sup>	±140	A
Maximum Power Dissipation	P <sub>D</sub>	80 (T <sub>C</sub> =25°C)	W
Single Pulse Avalanche Energy	E <sub>AS</sub> <sup>*2</sup>	400	mJ
Channel Temperature	T <sub>ch</sub>	150	°C
Storage Temperature	T <sub>stg</sub>	-55 to +150	°C

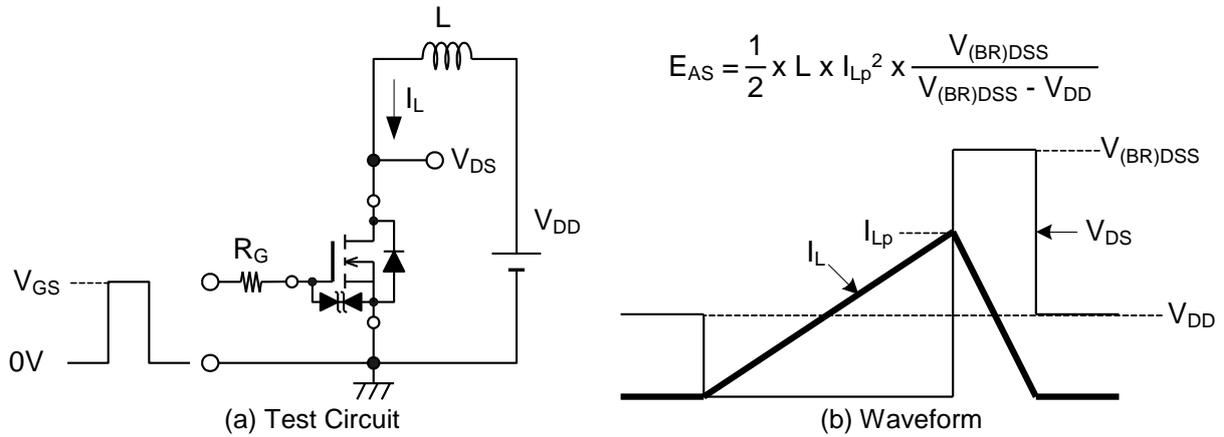
\*1: PW≤100us, duty cycle≤1%

\*2: V<sub>DD</sub>=20V, L=1mH, I<sub>L</sub>=20A, unclamped, R<sub>G</sub>=50Ω (See Fig. 1)

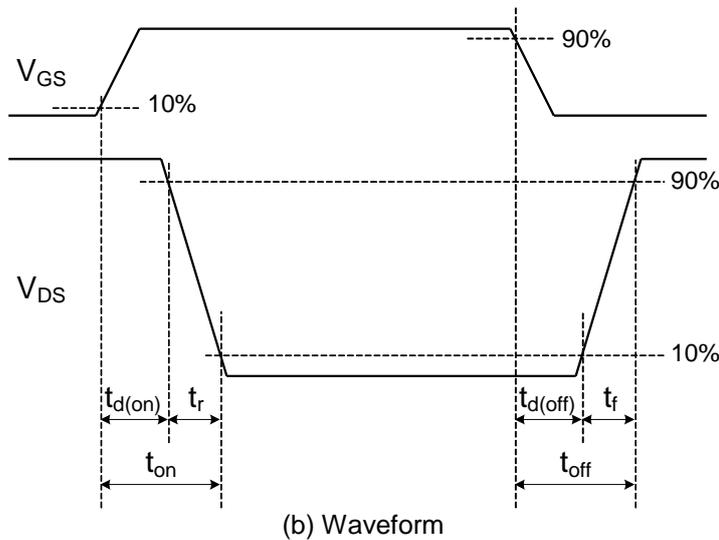
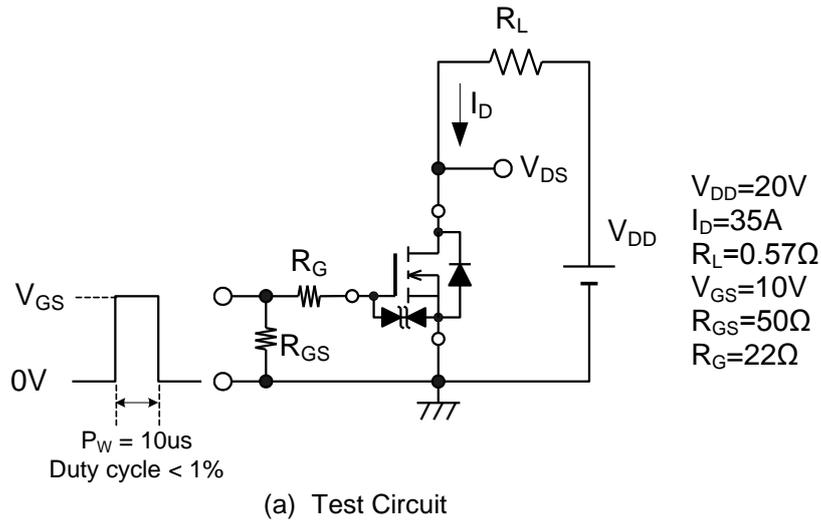
## Electric Characteristics

(Ta=25°C)

Characteristic	Symbol	Test Condition	Rating			Unit
			MIN	TYP	MAX	
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D=100\mu A, V_{GS}=0V$	40			V
Gate to Source Leakage Current	$I_{GSS}$	$V_{GS}=\pm 15V$			$\pm 10$	$\mu A$
Drain to Source Leakage Current	$I_{DSS}$	$V_{DS}=40V, V_{GS}=0V$			100	$\mu A$
Gate Threshold Voltage	$V_{TH}$	$V_{DS}=10V, I_D=1mA$	2.0	3.0	4.0	V
Forward Transconductance	$R_{e(yfs)}$	$V_{DS}=10V, I_D=35A$	30	50		S
Static Drain to Source On-resistance	$R_{DS(ON)}$	$I_D=35A, V_{GS}=10V$		5.0	6.0	m $\Omega$
Input Capacitance	$C_{iss}$	$V_{DS}=10V, V_{GS}=0V, f=1MHz$		5100		pF
Output Capacitance	$C_{oss}$			1200		
Reverse Transfer Capacitance	$C_{rss}$			860		
Turn-on Delay Time	$t_{d(on)}$	$I_D=35A, V_{DD} \doteq 20V, R_G=22\Omega, R_L=0.57\Omega, V_{GS}=10V$ See Fig.2		100		ns
Rise Time	$t_r$			100		
Turn-off Delay Time	$t_{d(off)}$			300		
Fall Time	$t_f$			130		
Source-Drain Diode Forward Voltage	$V_{SD}$	$I_{SD}=50A, V_{GS}=0V$		0.9	1.2	V
Source-Drain Diode Reverse Recovery Time	$t_{rr}$	$I_{SD}=25A, di/dt=50A/\mu s$		100		ns
Thermal Resistance between Junction and Case	$R_{th(ch-c)}$				1.56	$^{\circ}C/W$
Thermal Resistance between Junction and Ambient	$R_{th(ch-a)}$				62.5	$^{\circ}C/W$



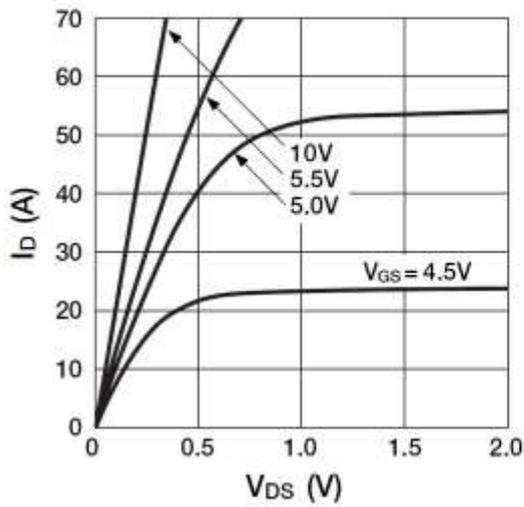
**Fig.1 Unclamped Inductive Test Method**



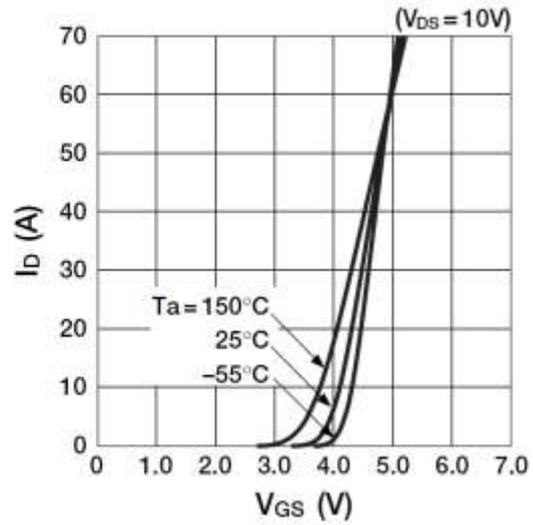
**Fig.2 Switching Time Test Method**

## Characteristic Curves

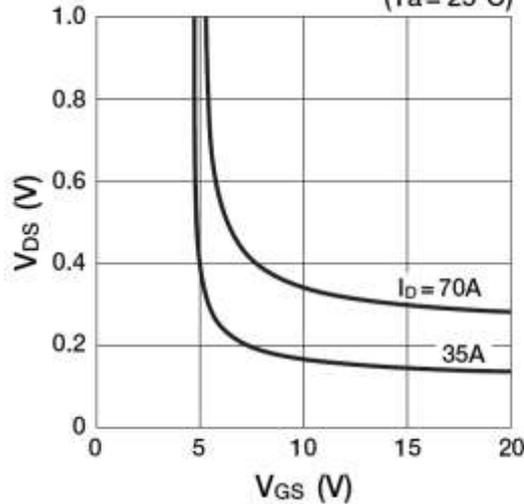
■  $I_D - V_{DS}$  Characteristics (typ.)



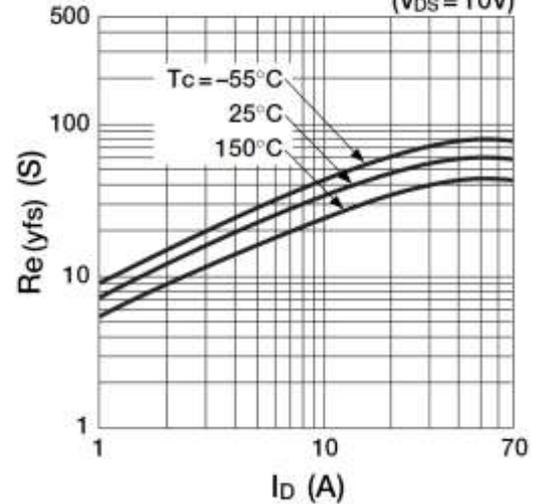
■  $I_D - V_{GS}$  Characteristics (typ.)



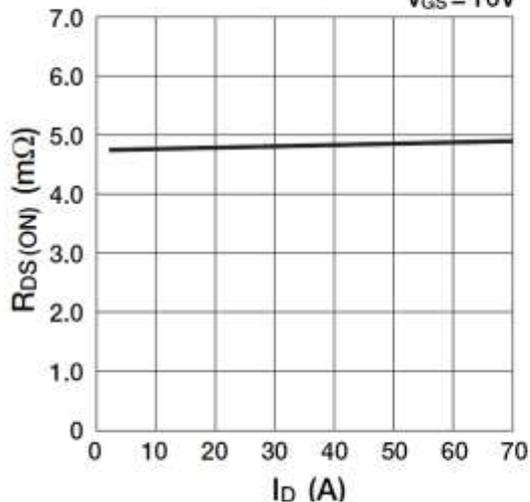
■  $V_{DS} - V_{GS}$  Characteristics (typ.)  
( $T_a = 25^\circ C$ )



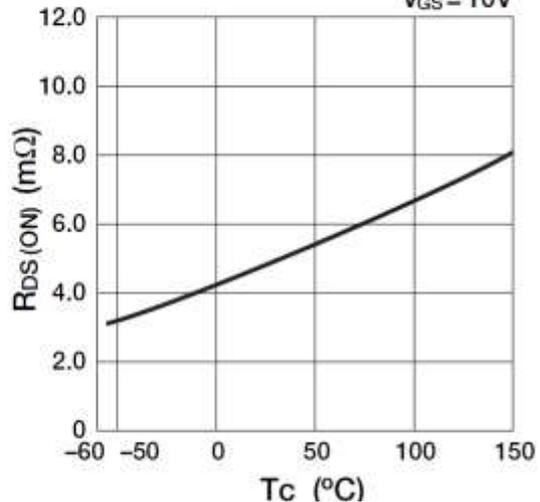
■  $Re(y_{fs}) - I_D$  Characteristics (typ.)  
( $V_{DS} = 10V$ )



■  $R_{DS(ON)} - I_D$  Characteristics (typ.)  
 $T_a = 25^\circ C$   
 $V_{GS} = 10V$

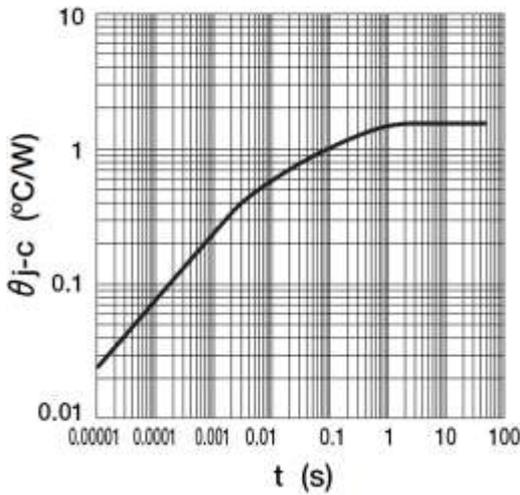


■  $R_{DS(ON)} - T_c$  Characteristics (typ.)  
 $I_D = 35A$   
 $V_{GS} = 10V$

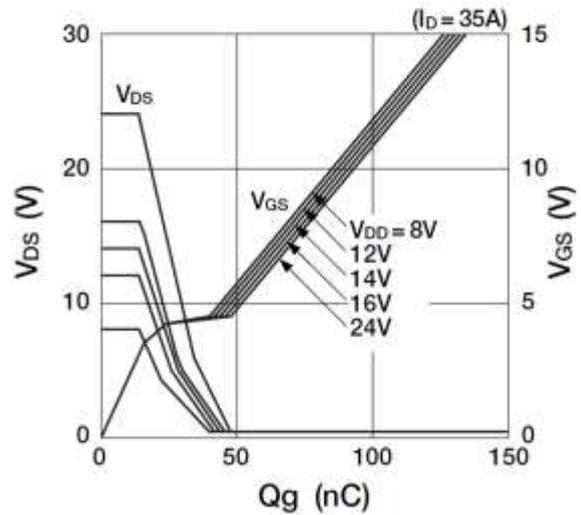


## Characteristic Curves

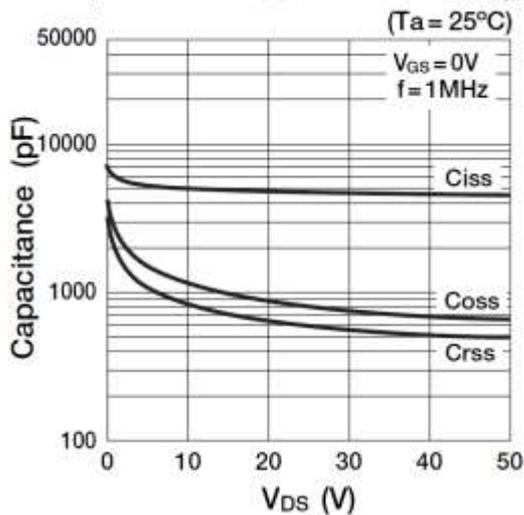
■  $\theta_{j-c} - t$  Characteristics (Single pulse)



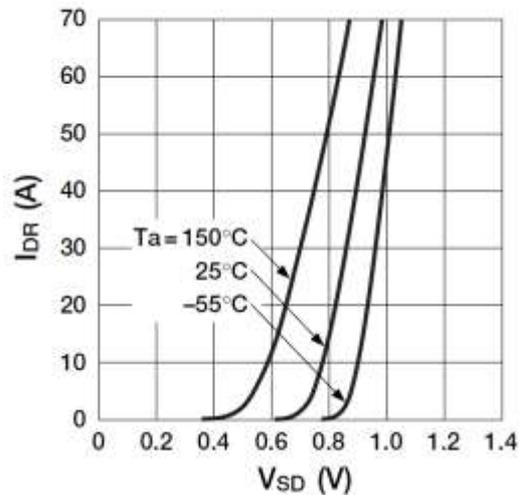
■ Dynamic I/O Characteristics (typ.)



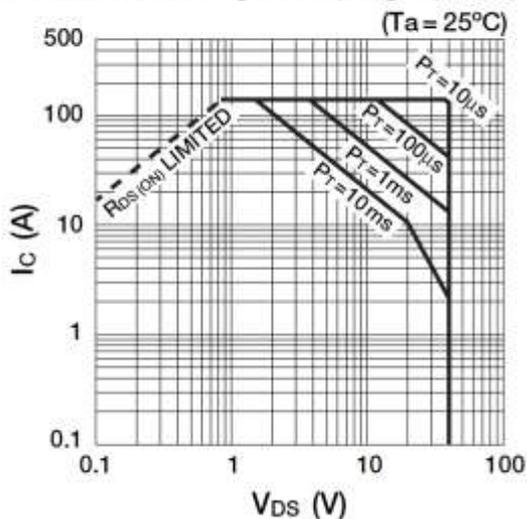
■ Capacitance— $V_{DS}$  Characteristics (typ.)



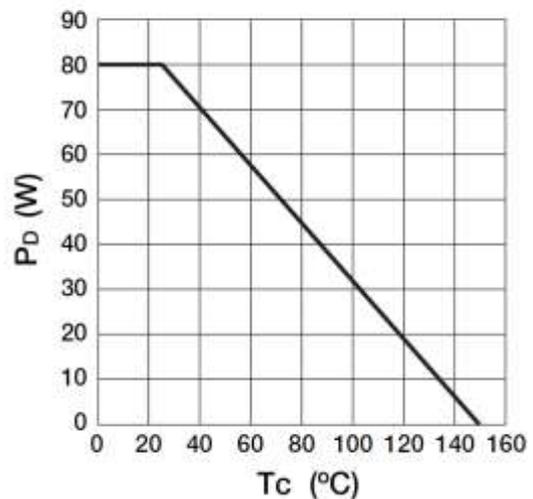
■  $I_{DR} - V_{SD}$  Characteristics (typ.)



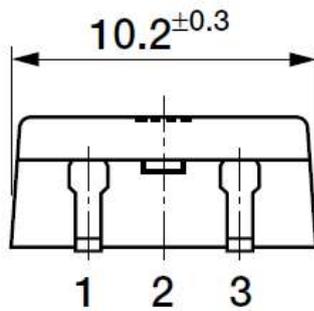
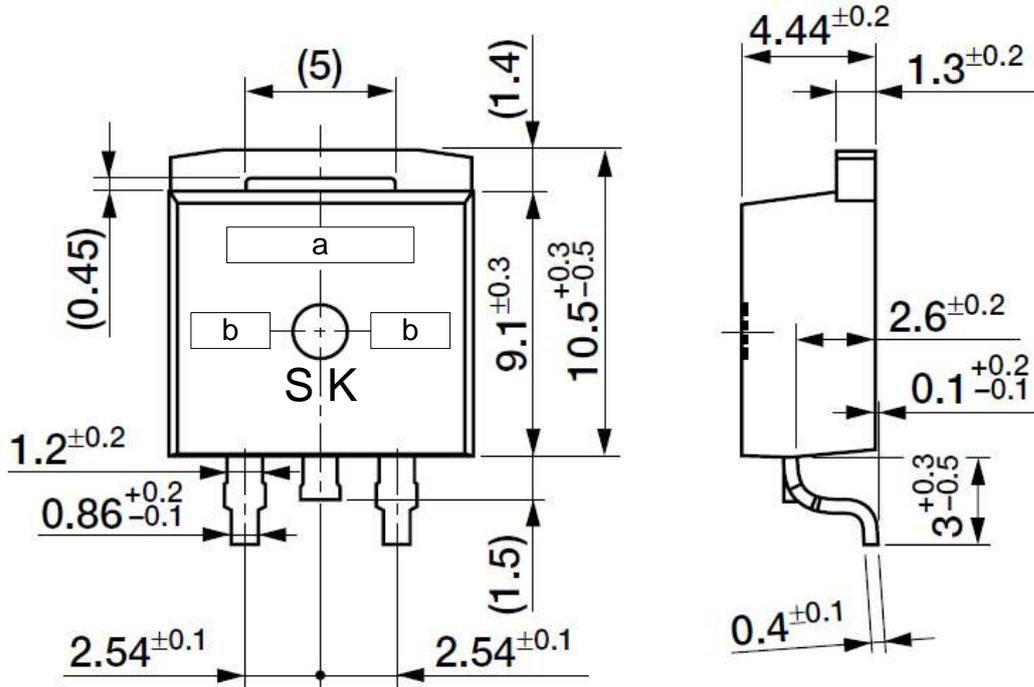
■ Safe Operating Area (single pulse)



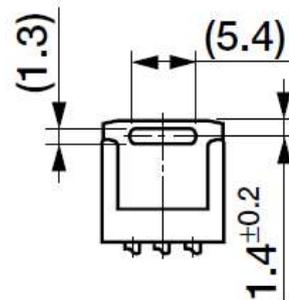
■  $P_D - T_C$  Characteristics



Outline (unit: mm)



- 1 Gate
- 2 Drain (back side)
- 3 Source



Details of the back (S=2/1)

Marking

- a. Type Number: K3800
- b. Lot Number
  - 1st letter: The last digit of year
  - 2nd letter: 1 to 9 for Jan to Sept, O for Oct, N for Nov, D for Dec
  - 3rd & 4th letter: day (01 to 31)

## Caution & Warning 1

### (1) Cautions for Storage

- Ensure that storage conditions comply with the standard temperature (5 to 35°C) and the standard relative humidity (around 40 to 75%) and avoid storage locations that experience extreme changes in temperature or humidity.
- Avoid locations where dust or harmful gases are present and avoid direct sunlight.
- Reinspect for rust leads and solderability that have been stored for a long time.

### (2) Cautions for characteristic Test and Handling

- When characteristic tests are carried out during inspection testing and other standard tests periods, protect the Power MOS FETs from surge of power from the testing device, shorts between the Power MOS FETs and the heatsink.

### (3) Silicone Grease

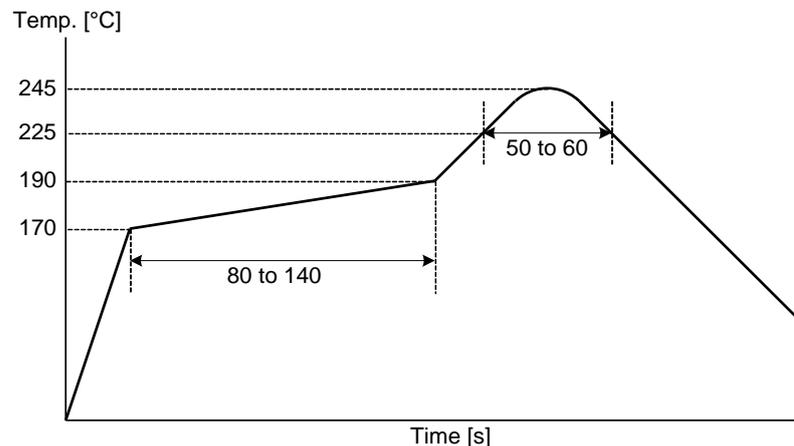
- When using a heatsink, please coat the back surface of the Power MOS FETs and both surfaces of the insulating plate with a thin layer of silicone grease to improve heat transfer between the Power MOS FETs and the heatsink. There are types of silicone grease of which oil ingredients may permeate the inside of products. Since there is a possibility that it may shorten the lifetime of the products, please pay sufficient attention to the choice of the silicone grease.

#### Recommended Silicone grease

- G746 (Shin-Etsu Chemical Co., Ltd.)
- YG6260 (MOMENTIVE performance materials)
- SC102 (Dow Corning Toray Co., Ltd.)

### (4) Soldering Temperature

- Recommended soldering conditions (Maximum)  
Refer to following Fig. (Reflow Soldering)  
260°C 10sec. (Flow Soldering)  
350°C 3sec. (Solder iron)  
at a distance of 1.5mm from the main body of Power MOS FETs



### (5) Considerations to protect Power MOS FETs from Electrostatic Discharge

- When handling power MOS FETs device, operator must be grounded. Grounded wrist straps be worn and should have at least 1MΩ of resistance near operators to ground to prevent shock hazard.
- Workbenches where the devices are handled should be grounded and be provided with conductive table and floor mats.
- When using measuring equipment such as a curve tracer, the equipment should also be grounded.
- When soldering the devices, the head of a soldering iron or a solder bath must be grounded in other to prevent leak voltage generated by them from being applied to the devices.
- The devices should always be stored and transported in our shipping containers or conductive containers, or be wrapped up in aluminum foil.

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## Caution & Warning 2

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In addition, it should be noted that since power devices or IC's including power devices have large self-heating value, the degree of derating of junction temperature ( $T_j$ ) affects the reliability significantly.
  
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